



US00D354923S

United States Patent [19]

[11] Patent Number: **Des. 354,923**

Nightingale

[45] Date of Patent: **** Jan. 31, 1995**

[54] **PROBING HEAD FOR AN ELECTRICAL TEST PROBE**

4,533,864 8/1985 Austin 324/72.5 X
4,701,702 10/1987 Krüger 324/72.5 X

[75] Inventor: **Mark W. Nightingale**, Washougal, Wash.

Primary Examiner—Alan P. Douglas
Assistant Examiner—Antoine D. Davis
Attorney, Agent, or Firm—William K. Bucher

[73] Assignee: **Tektronix, Inc.**, Wilsonville, Oreg.

[57] **CLAIM**

[**] Term: **14 Years**

The ornamental design for a probing head for an electrical test probe, as shown and described.

[21] Appl. No.: **18,212**

DESCRIPTION

[22] Filed: **Jan. 31, 1994**

[52] U.S. Cl. **D10/80; D10/78**

[58] Field of Search **D10/80, 78; 324/72.5, 324/156 P, 538**

FIG. 1 is a top, front, and left side perspective view of the probing head for an electrical test probe showing my new design;

FIG. 2 is a left side elevation view having a mirrored right side elevation view of the probing head for an electrical test probe showing my new design;

FIG. 3 is a top plan view thereof;

FIG. 4 is a bottom plan view thereof;

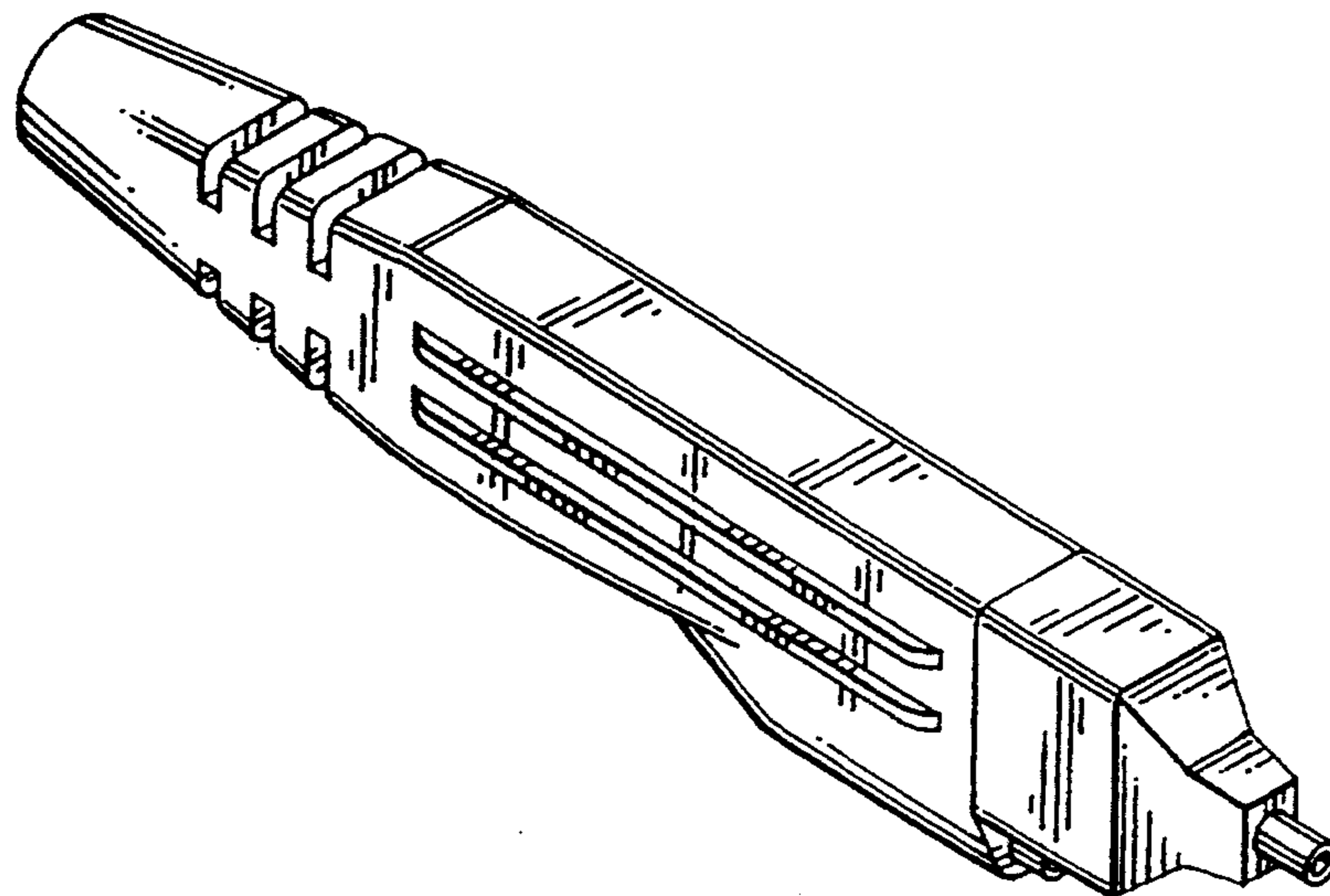
FIG. 5 is a front elevation view thereof; and,

FIG. 6 is a rear elevation view thereof.

[56] **References Cited**

U.S. PATENT DOCUMENTS

4,034,293 7/1977 Roch 324/72.5 X
4,151,465 4/1979 Lenz 324/72.5 X
4,491,788 1/1985 Zandonatti 324/72.5



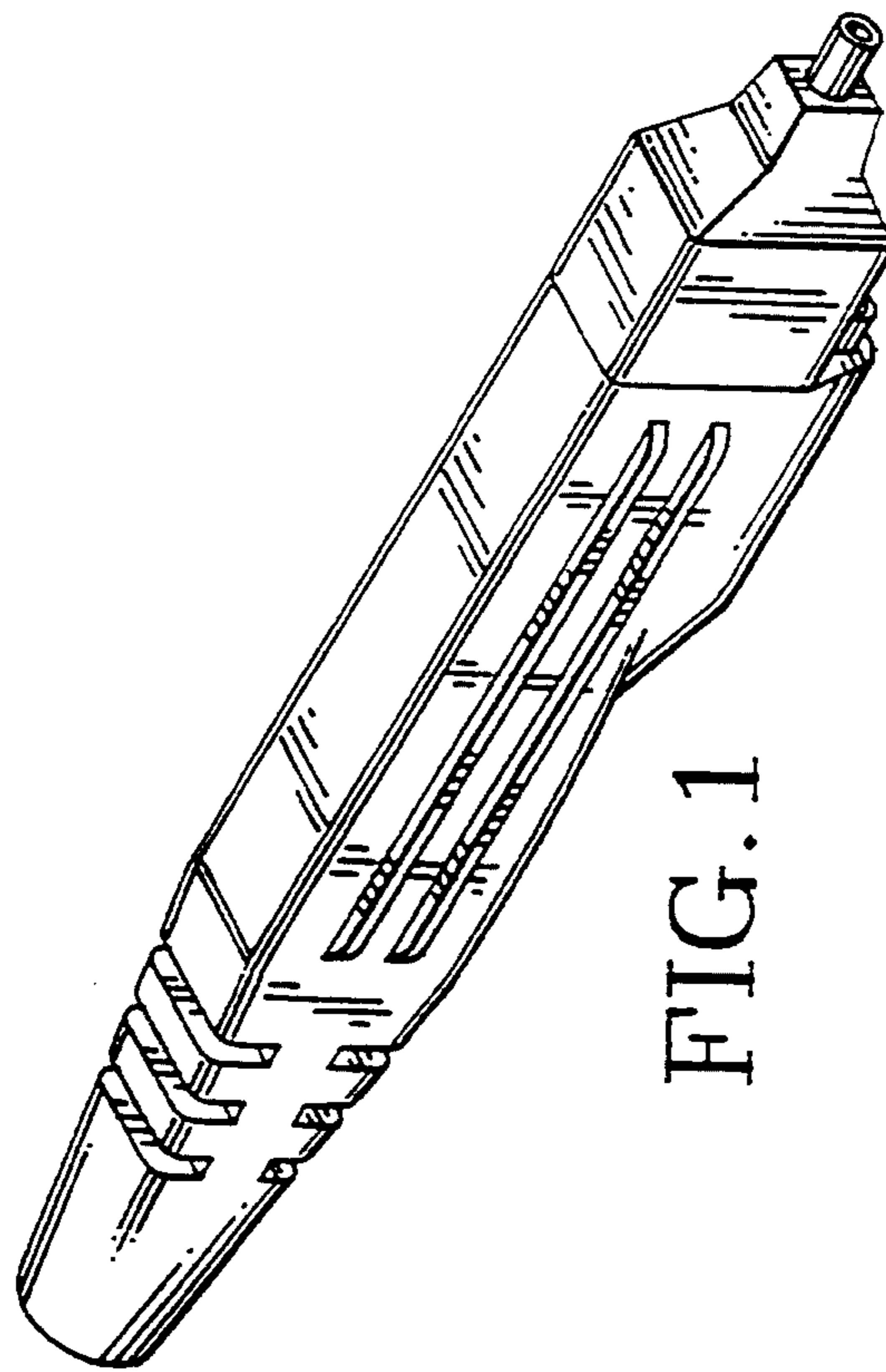


FIG. 1

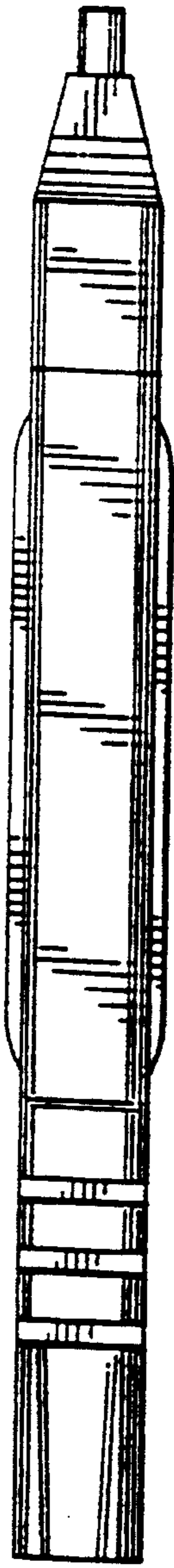


FIG. 3

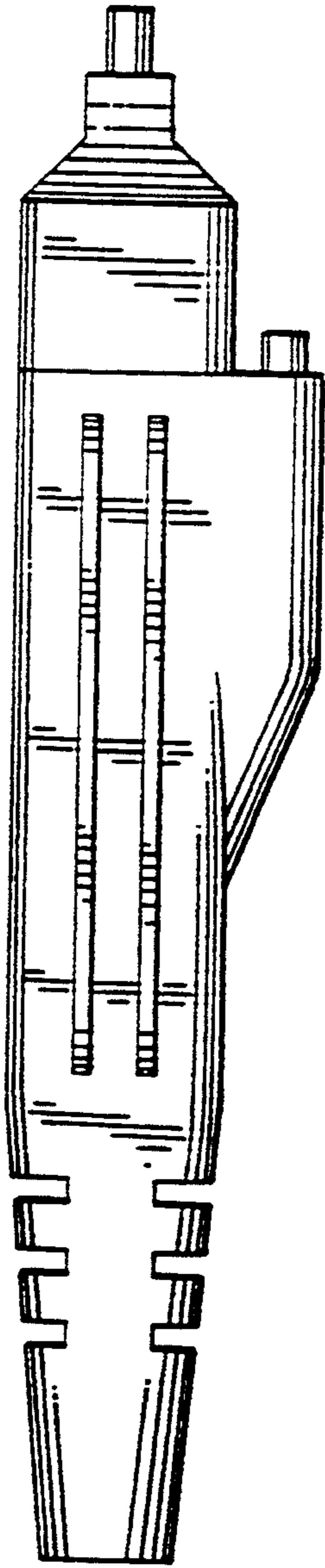


FIG. 2



FIG. 4

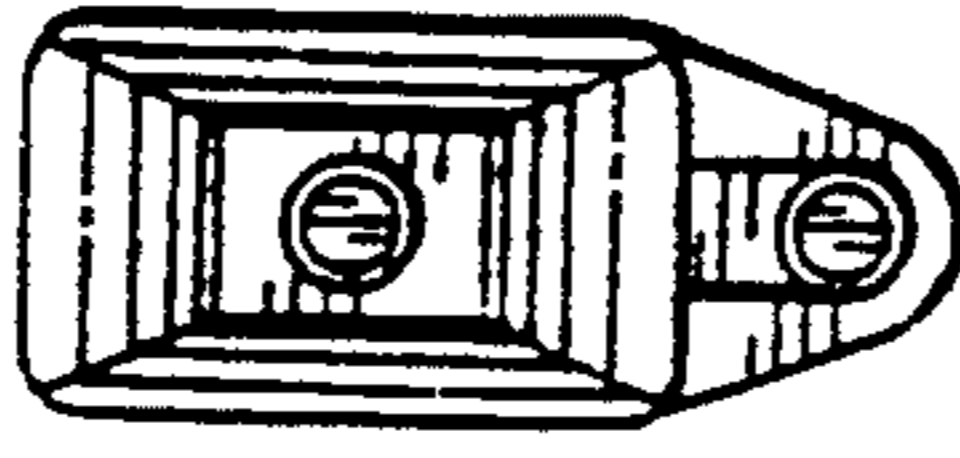


FIG. 5

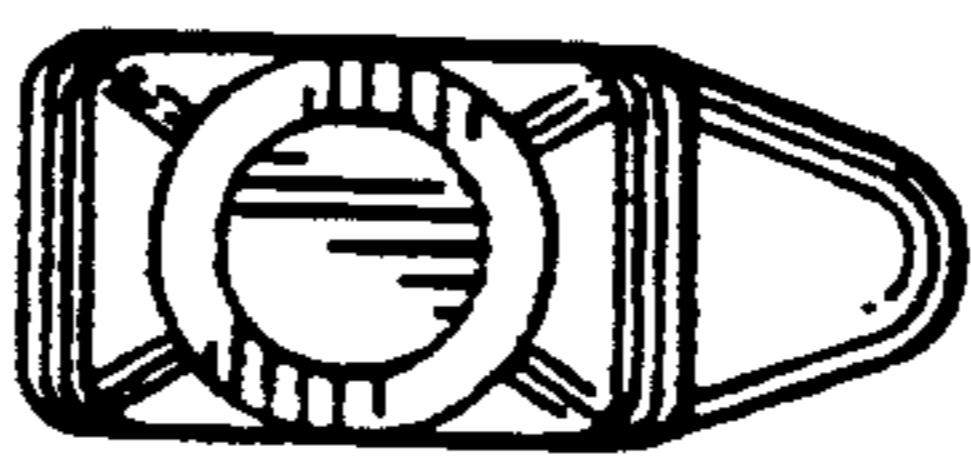


FIG. 6